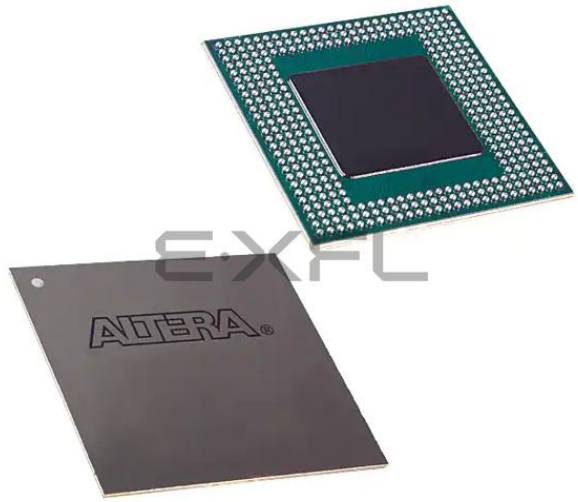

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	832
Number of Logic Elements/Cells	8320
Total RAM Bits	106496
Number of I/O	271
Number of Gates	526000
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	356-LBGA
Supplier Device Package	356-BGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep20k200cb356c8es

After an APEX 20KC device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Real-time changes can be made during system operation, enabling innovative reconfigurable computing applications.

APEX 20KC devices are supported by the Altera Quartus II development system, a single, integrated package that offers HDL and schematic design entry, compilation and logic synthesis, full simulation and worst-case timing analysis, SignalTap logic analysis, and device configuration. The Quartus II software runs on Windows-based PCs, Sun SPARCstations, and HP 9000 Series 700/800 workstations.

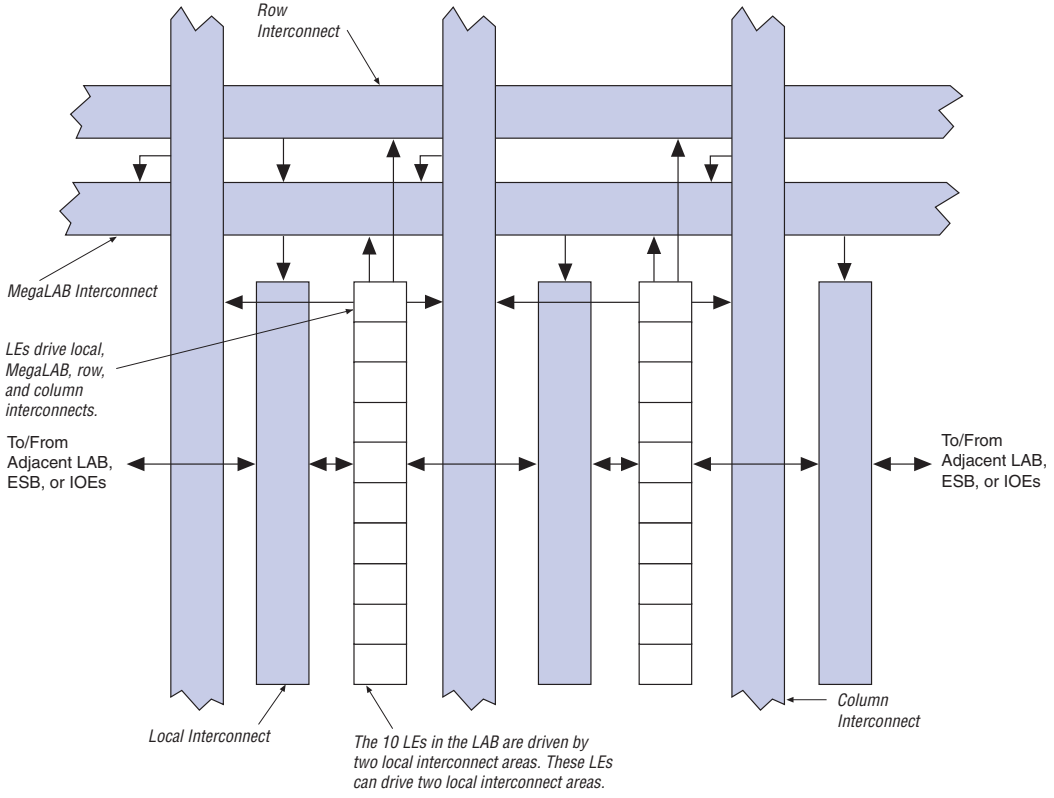
The Quartus II software provides NativeLink interfaces to other industry-standard PC- and UNIX workstation-based EDA tools. For example, designers can invoke the Quartus II software from within third-party design tools. Further, the Quartus II software contains built-in optimized synthesis libraries; synthesis tools can use these libraries to optimize designs for APEX 20KC devices. For example, the Synopsys Design Compiler library, supplied with the Quartus II development system, includes DesignWare functions optimized for the APEX 20KC architecture.

Functional Description

APEX 20KC devices incorporate LUT-based logic, product-term-based logic, and memory into one device on an all-copper technology process. Signal interconnections within APEX 20KC devices (as well as to and from device pins) are provided by the FastTrack interconnect—a series of fast, continuous row and column channels that run the entire length and width of the device.

Each I/O pin is fed by an I/O element (IOE) located at the end of each row and column of the FastTrack interconnect. Each IOE contains a bidirectional I/O buffer and a register that can be used as either an input or output register to feed input, output, or bidirectional signals. When used with a dedicated clock pin, these registers provide exceptional performance. IOEs provide a variety of features, such as 3.3-V, 64-bit, 66-MHz PCI compliance; JTAG BST support; slew-rate control; and tri-state buffers. APEX 20KC devices offer enhanced I/O support, including support for 1.8-V I/O, 2.5-V I/O, LVCMOS, LVTTL, LVPECL, 3.3-V PCI, PCI-X, LVDS, GTL+, SSTL-2, SSTL-3, HSTL, CTT, and 3.3-V AGP I/O standards.

Figure 3. LAB Structure



Each LAB contains dedicated logic for driving control signals to its LEs and ESBs. The control signals include clock, clock enable, asynchronous clear, asynchronous preset, asynchronous load, synchronous clear, and synchronous load signals. A maximum of six control signals can be used at a time. Although synchronous load and clear signals are generally used when implementing counters, they can also be used with other functions.

Each LAB can use two clocks and two clock enable signals. Each LAB's clock and clock enable signals are linked (e.g., any LE in a particular LAB using `CLK1` will also use `CLKENA1`). LEs with the same clock but different clock enable signals either use both clock signals in one LAB or are placed into separate LABs.

If both the rising and falling edges of a clock are used in a LAB, both LAB-wide clock signals are used.

The APEX 20KC architecture provides two types of dedicated high-speed data paths that connect adjacent LEs without using local interconnect paths: carry chains and cascade chains. A carry chain supports high-speed arithmetic functions such as counters and adders, while a cascade chain implements wide-input functions such as equality comparators with minimum delay. Carry and cascade chains connect LEs 1 through 10 in an LAB and all LABs in the same MegaLAB structure.

Carry Chain

The carry chain provides a very fast carry-forward function between LEs. The carry-in signal from a lower-order bit drives forward into the higher-order bit via the carry chain, and feeds into both the LUT and the next portion of the carry chain. This feature allows the APEX 20KC architecture to implement high-speed counters, adders, and comparators of arbitrary width. Carry chain logic can be created automatically by the Quartus II Compiler during design processing, or manually by the designer during design entry. Parameterized functions such as DesignWare functions from Synopsys and library of parameterized modules (LPM) functions automatically take advantage of carry chains for the appropriate functions.

The Quartus II Compiler creates carry chains longer than ten LEs by automatically linking LABs together. For enhanced fitting, a long carry chain skips alternate LABs in a MegaLAB structure. A carry chain longer than one LAB skips either from an even-numbered LAB to the next even-numbered LAB, or from an odd-numbered LAB to the next odd-numbered LAB. For example, the last LE of the first LAB in the upper-left MegaLAB structure carries to the first LE of the third LAB in the MegaLAB structure.

Figure 6 shows how an *n*-bit full adder can be implemented in *n* + 1 LEs with the carry chain. One portion of the LUT generates the sum of two bits using the input signals and the carry-in signal; the sum is routed to the output of the LE. The register can be bypassed for simple adders or used for accumulator functions. Another portion of the LUT and the carry chain logic generates the carry-out signal, which is routed directly to the carry-in signal of the next-higher-order bit. The final carry-out signal is routed to an LE, where it is driven onto the local, MegaLAB, or FastTrack interconnect routing structures.

Table 8. APEX 20KC Routing Scheme

Source	Destination								
	Row I/O Pin	Column I/O Pin	LE	ESB	Local Interconnect	MegaLAB Interconnect	Row FastTrack Interconnect	Column FastTrack Interconnect	FastRow Interconnect
Row I/O pin					✓	✓	✓	✓	
Column I/O pin								✓	✓
LE					✓	✓	✓	✓	
ESB					✓	✓	✓	✓	
Local interconnect	✓	✓	✓	✓					
MegaLAB interconnect					✓				
Row FastTrack interconnect						✓		✓	
Column FastTrack interconnect						✓	✓		
FastRow interconnect					✓				

Product-Term Logic

The product-term portion of the MultiCore architecture is implemented with the ESB. The ESB can be configured to act as a block of macrocells on an ESB-by-ESB basis. Each ESB is fed by 32 inputs from the adjacent local interconnect; therefore, it can be driven by the MegaLAB interconnect or the adjacent LAB. Also, nine ESB macrocells feed back into the ESB through the local interconnect for higher performance. Dedicated clock pins, global signals, and additional inputs from the local interconnect drive the ESB control signals.

In product-term mode, each ESB contains 16 macrocells. Each macrocell consists of two product terms and a programmable register. Figure 13 shows the ESB in product-term mode.

ESBs can implement synchronous RAM, which is easier to use than asynchronous RAM. A circuit using asynchronous RAM must generate the RAM write enable (WE) signal, while ensuring that its data and address signals meet setup and hold time specifications relative to the WE signal. In contrast, the ESB's synchronous RAM generates its own WE signal and is self-timed with respect to the global clock. Circuits using the ESB's self-timed RAM must only meet the setup and hold time specifications of the global clock.

ESB inputs are driven by the adjacent local interconnect, which in turn can be driven by the FastTrack or MegaLAB interconnect. Because the ESB can be driven by the local interconnect, an adjacent LE can drive it directly for fast memory access. ESB outputs drive the FastTrack and MegaLAB interconnects. In addition, ten ESB outputs, nine of which are unique output lines, drive the local interconnect for fast connection to adjacent LEs or for fast feedback product-term logic.

When implementing memory, each ESB can be configured in any of the following sizes: 128 × 16, 256 × 8, 512 × 4, 1,024 × 2, or 2,048 × 1. By combining multiple ESBs, the Quartus II software implements larger memory blocks automatically. For example, two 128 × 16 RAM blocks can be combined to form a 128 × 32 RAM block, and two 512 × 4 RAM blocks can be combined to form a 512 × 8 RAM block. Memory performance does not degrade for memory blocks up to 2,048 words deep. Each ESB can implement a 2,048-word-deep memory; the ESBs are used in parallel, eliminating the need for any external control logic and its associated delays.

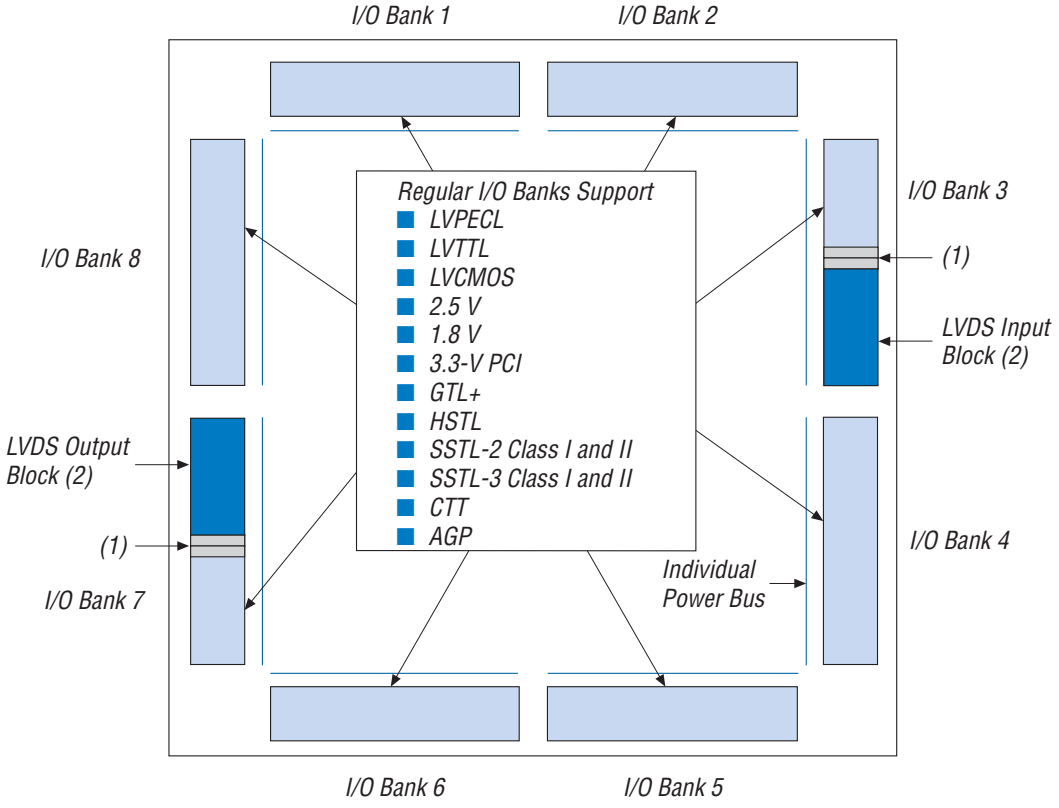
To create a high-speed memory block that is more than 2,048 words deep, ESBs drive tri-state lines. Each tri-state line connects all ESBs in a column of MegaLAB structures, and drives the MegaLAB interconnect and row and column FastTrack interconnect throughout the column. Each ESB incorporates a programmable decoder to activate the tri-state driver appropriately. For instance, to implement 8,192-word-deep memory, four ESBs are used. Eleven address lines drive the ESB memory, and two more drive the tri-state decoder. Depending on which 2,048-word memory page is selected, the appropriate ESB driver is turned on, driving the output to the tri-state line. The Quartus II software automatically combines ESBs with tri-state lines to form deeper memory blocks. The internal tri-state control logic is designed to avoid internal contention and floating lines. See Figure 18.

CAM is used for high-speed search operations. When searching for data within a RAM block, the search is performed serially. Thus, finding a particular data word can take many cycles. CAM searches all addresses in parallel and outputs the address storing a particular word. When a match is found, a match flag is set high. Figure 23 shows the CAM block diagram.

The register in the APEX 20KC IOE can be programmed to power-up high or low after configuration is complete. If it is programmed to power-up low, an asynchronous clear can control the register. If it is programmed to power-up high, an asynchronous preset can control the register. This feature is useful for cases where the APEX 20KC device controls an active-low input or another device; it prevents inadvertent activation of the input upon power-up.

Figure 25 shows how fast bidirectional I/O pins are implemented in APEX 20KC devices. This feature is useful for cases where the APEX 20KC device controls an active-low input or another device; it prevents inadvertent activation of the input upon power-up.

Figure 28. APEX 20KC I/O Banks



Notes to Figure 28:

(1) For more information on placing I/O pins in LVDS blocks, refer to the "Guidelines for Using LVDS Blocks" section in *Application Note 120 (Using LVDS in APEX 20KE Devices)*.

(2) If the LVDS input and output blocks are not used for LVDS, they can support all of the I/O standards and can be used as input, output, or bidirectional pins with V_{CCIO} set to 3.3 V, 2.5 V, or 1.8 V.

Power Sequencing & Hot Socketing

Because APEX 20KC devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the V_{CCIO} and V_{CCINT} power supplies may be powered in any order.

Open-drain output pins on APEX 20KC devices (with a series resistor and a pull-up resistor to the 5.0-V supply) can drive 5.0-V CMOS input pins that require a V_{IH} of 3.5 V. When the pin is inactive, the trace will be pulled up to 5.0 V by the resistor. The open-drain pin will only drive low or tri-state; it will never drive high. The rise time is dependent on the value of the pull-up resistor and load impedance. The I_{OL} current specification should be considered when selecting a pull-up resistor.

ClockLock & ClockBoost Features

APEX 20KC devices support the ClockLock and ClockBoost clock management features, which are implemented with PLLs. The ClockLock circuitry uses a synchronizing PLL that reduces the clock delay and skew within a device. This reduction minimizes clock-to-output and setup times while maintaining zero hold times. The ClockBoost circuitry, which provides a clock multiplier, allows the designer to enhance device area efficiency by sharing resources within the device. The ClockBoost circuitry allows the designer to distribute a low-speed clock and multiply that clock on-device. APEX 20KC devices include a high-speed clock tree; unlike ASICs, the user does not have to design and optimize the clock tree. The ClockLock and ClockBoost features work in conjunction with the APEX 20KC device's high-speed clock to provide significant improvements in system performance and bandwidth. APEX 20KC devices in -7 and -8 speed grades have PLLs and support the ClockLock and ClockBoost features.

The ClockLock and ClockBoost features in APEX 20KC devices are enabled through the Quartus II software. External devices are not required to use these features.

APEX 20KC ClockLock Feature

APEX 20KC devices include up to four PLLs, which can be used independently. Two PLLs are designed for either general-purpose use or LVDS use (on devices that support LVDS I/O pins). The remaining two PLLs are designed for general-purpose use. The EP20K200C devices have two PLLs; the EP20K400C and larger devices have four PLLs.

The following sections describe some of the features offered by the APEX 20KC PLLs.

External PLL Feedback

The ClockLock circuit's output can be driven off-chip to clock other devices in the system; further, the feedback loop of the PLL can be routed off-chip. This feature allows the designer to exercise fine control over the I/O interface between the APEX 20KC device and another high-speed device, such as SDRAM.

Clock Multiplication

The APEX 20KC ClockBoost circuit can multiply or divide clocks by a programmable number. The clock can be multiplied by $m/(n \times k)$, where m and k range from 2 to 160 and n ranges from 1 to 16. Clock multiplication and division can be used for time-domain multiplexing and other functions, which can reduce design LE requirements.

Clock Phase & Delay Adjustment

The APEX 20KC ClockShift feature allows the clock phase and delay to be adjusted. The clock phase can be adjusted by 90° steps. The clock delay can be adjusted to increase or decrease the clock delay by an arbitrary amount, up to one clock period.

LVDS Support

All APEX 20KC devices support differential LVDS buffers on the input and output clock signals that interface with external devices. This is controlled in the Quartus II software by assigning the clock pins with an LVDS I/O standard assignment.

Two high-speed PLLs are designed to support the LVDS interface. When using LVDS, the I/O clock runs at a slower rate than the data transfer rate. Thus, PLLs are used to multiply the I/O clock internally to capture the LVDS data. For example, an I/O clock may run at 105 MHz to support 840 Mbps LVDS data transfer. In this example, the PLL multiplies the incoming clock by eight to support the high-speed data transfer. You can use PLLs in EP20K400C and larger devices for high-speed LVDS interfacing.

Lock Signals

The APEX 20KC ClockLock circuitry supports individual `LOCK` signals. The `LOCK` signal drives high when the ClockLock circuit has locked onto the input clock. The `LOCK` signals are optional for each ClockLock circuit; when not used, they are I/O pins.

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

All APEX 20KC devices provide JTAG BST circuitry that complies with the IEEE Std. 1149.1-1990 specification. JTAG boundary-scan testing can be performed before or after configuration, but not during configuration. APEX 20KC devices can also use the JTAG port for configuration with the Quartus II software or with hardware using either Jam Files (**.jam**) or Jam Byte-Code Files (**.jbc**). Finally, APEX 20KC devices use the JTAG port to monitor the logic operation of the device with the SignalTap embedded logic analyzer. APEX 20KC devices support the JTAG instructions shown in Table 13.

Table 13. APEX 20KC JTAG Instructions

JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap embedded logic analyzer.
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
USERCODE	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
ICR Instructions	Used when configuring an APEX 20KC device via the JTAG port with a MasterBlaster™ or ByteBlasterMV™ download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor.
SignalTap Instructions	Monitors internal device operation with the SignalTap embedded logic analyzer.

Table 22. LVCMOS I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Units
V_{CCIO}	Power supply voltage range		3.0	3.6	V
V_{IH}	High-level input voltage		2.0	V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
I_I	Input pin leakage current	V_{IN} = 0 V or 3.3 V	–10	10	µA
V_{OH}	High-level output voltage	V_{CCIO} = 3.0 V I_{OH} = –0.1 mA *(1)*	V_{CCIO} – 0.2		V
V_{OL}	Low-level output voltage	V_{CCIO} = 3.0 V I_{OL} = 0.1 mA *(2)*		0.2	V

Table 23. 2.5-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Units
V_{CCIO}	Output supply voltage		2.375	2.625	V
V_{IH}	High-level input voltage		1.7	V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
I_I	Input pin leakage current	V_{IN} = 0 V or 3.3 V	–10	10	µA
V_{OH}	High-level output voltage	I_{OH} = –0.1 mA *(1)*	2.1		V
		I_{OH} = –1 mA *(1)*	2.0		V
		I_{OH} = –2 mA *(1)*	1.7		V
V_{OL}	Low-level output voltage	I_{OL} = 0.1 mA *(2)*		0.2	V
		I_{OL} = 1 mA *(2)*		0.4	V
		I_{OL} = 2 mA *(2)*		0.7	V

Table 28. GTL+ I/O Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Units
V_{TT}	Termination voltage		1.35	1.5	1.65	V
V_{REF}	Reference voltage		0.88	1.0	1.12	V
V_{IH}	High-level input voltage		V_{REF} + 0.1			V
V_{IL}	Low-level input voltage				V_{REF} – 0.1	V
V_{OL}	Low-level output voltage	I_{OL} = 36 mA *(2)*			0.65	V

Table 29. SSTL-2 Class I Specifications

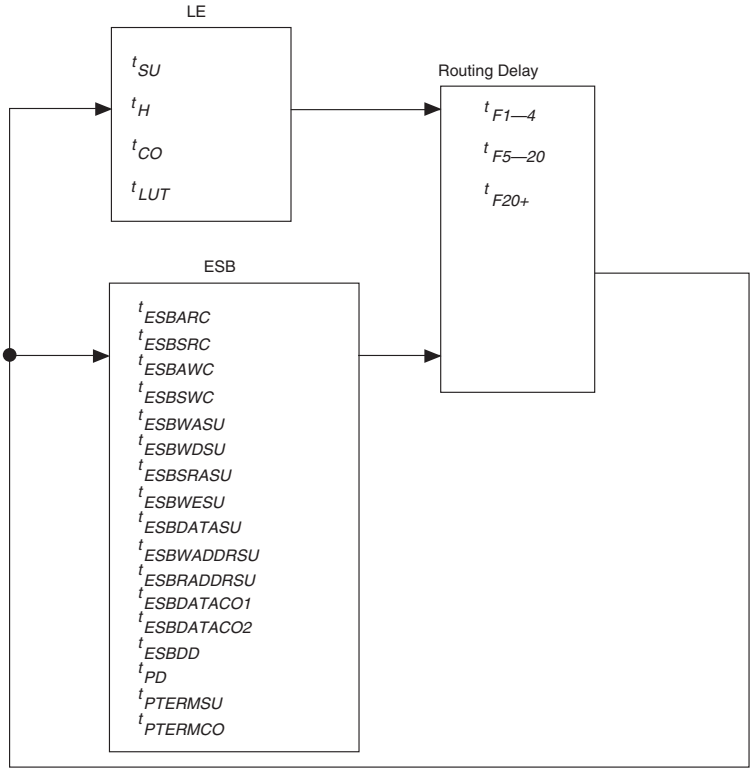
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Units
V_{CCIO}	I/O supply voltage		2.375	2.5	2.625	V
V_{TT}	Termination voltage		V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage		1.15	1.25	1.35	V
V_{IH}	High-level input voltage		V_{REF} + 0.18		V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage		–0.3		V_{REF} – 0.18	V
V_{OH}	High-level output voltage	I_{OH} = –7.6 mA *(1)*	V_{TT} + 0.57			V
V_{OL}	Low-level output voltage	I_{OL} = 7.6 mA *(2)*			V_{TT} – 0.57	V

Timing Model

The high-performance FastTrack and MegaLAB interconnect routing resources ensure predictable performance, accurate simulation, and accurate timing analysis. This predictable performance contrasts with that of FPGAs, which use a segmented connection scheme and therefore have unpredictable performance.

Figure 32 shows the f_{MAX} timing model for APEX 20KC devices.

Figure 32. f_{MAX} Timing Model



Figures 33 and 34 show the asynchronous and synchronous timingwaveforms, respectively, for the ESB macroparameters in Table 37.

Table 37. APEX 20KC f_{MAX} ESB Timing Parameters	
Symbol	**Parameter**
t_{ESBARC}	ESB asynchronous read cycle time
t_{ESBSRC}	ESB synchronous read cycle time
t_{ESBAWC}	ESB asynchronous write cycle time
t_{ESBSWC}	ESB synchronous write cycle time
$t_{ESBWASU}$	ESB write address setup time with respect to WE
t_{ESBWAH}	ESB write address hold time with respect to WE
$t_{ESBWDSU}$	ESB data setup time with respect to WE
t_{ESBWDH}	ESB data hold time with respect to WE
$t_{ESBRASU}$	ESB read address setup time with respect to RE
t_{ESBRAH}	ESB read address hold time with respect to RE
$t_{ESBWESU}$	ESB WE setup time before clock when using input register
$t_{ESBDATASU}$	ESB data setup time before clock when using input register
$t_{ESBWADDRSU}$	ESB write address setup time before clock when using input registers
$t_{ESBRADDRSU}$	ESB read address setup time before clock when using input registers
$t_{ESBDATACO1}$	ESB clock-to-output delay when using output registers
$t_{ESBDATACO2}$	ESB clock-to-output delay without output registers
t_{ESBDD}	ESB data-in to data-out delay for RAM mode
t_{PD}	ESB macrocell input to non-registered output
$t_{PTERMSU}$	ESB macrocell register setup time before clock
$t_{PTERMCO}$	ESB macrocell register clock-to-output delay

Table 38. APEX 20KC f_{MAX} Routing Delays	
Symbol	**Parameter**
t_{F1-4}	Fan-out delay estimate using local interconnect
t_{F5-20}	Fan-out delay estimate using MegaLab interconnect
t_{F20+}	Fan-out delay estimate using FastTrack interconnect

Table 41. APEX 20KC External Bidirectional Timing Parameters Note (1)		
Symbol	**Parameter**	**Condition**
$t_{INSUBIDIR}$	Setup time for bidirectional pins with global clock at LAB-adjacent input register	
$t_{INHBIDIR}$	Hold time for bidirectional pins with global clock at LAB-adjacent input register	
$t_{OUTCOBIDIR}$	Clock-to-output delay for bidirectional pins with global clock at IOE register	(2)
$t_{XZBIDIR}$	Synchronous output enable register to output buffer disable delay	(2)
$t_{ZXBIDIR}$	Synchronous output enable register to output buffer enable delay	(2)
$t_{INSUBIDIRPLL}$	Setup time for bidirectional pins with PLL clock at LAB-adjacent input register	
$t_{INHBIDIRPLL}$	Hold time for bidirectional pins with PLL clock at LAB-adjacent input register	
$t_{OUTCOBIDIRPLL}$	Clock-to-output delay for bidirectional pins with PLL clock at IOE register	(2)
$t_{XZBIDIRPLL}$	Synchronous output enable register to output buffer disable delay with PLL	(2)
$t_{ZXBIDIRPLL}$	Synchronous output enable register to output buffer enable delay with PLL	(2)

Notes to Tables 40 and 41:
(1) These timing parameters are sample-tested only.
(2) For more information, refer to Table 43.

Tables 42 and 43 define the timing delays for each I/O standard. Some output standards require test load circuits for AC timing measurements as shown in Figures 36 through 38.

Table 42. APEX 20KC Selectable I/O Standard Input Adder Delays (Part 1 of 2) Note (1)		
Symbol	**Parameter**	**Condition**
LVCMOS	Input adder delay for the LVCMOS I/O standard	
LVTTL	Input adder delay for the LVTTL I/O standard	
2.5 V	Input adder delay for the 2.5-V I/O standard	
1.8 V	Input adder delay for the 1.8-V I/O standard	
PCI	Input adder delay for the PCI I/O standard	
GTl+	Input adder delay for the GTL+ I/O standard	
SSTL-3 Class I	Input adder delay for the SSTL-3 Class I I/O standard	
SSTL-3 Class II	Input adder delay for the SSTL-3 Class II I/O standard	
SSTL-2 Class I	Input adder delay for the SSTL -2 Class I I/O standard	
SSTL-2 Class II	Input adder delay for the SSTL -2 Class II I/O standard	

Table 42. APEX 20KC Selectable I/O Standard Input Adder Delays (Part 2 of 2) *Note (1)*		
Symbol	**Parameter**	**Condition**
LVDS	Input adder delay for the LVDS I/O standard	
CTT	Input adder delay for the CTT I/O standard	
AGP	Input adder delay for the AGP I/O standard	

Table 43. APEX 20KC Selectable I/O Standard Output Adder Delays *Note (1)*		
Symbol	**Parameter**	**Condition**
LVCMOS	Output adder delay for the LVCMOS I/O standard	
LVTTL	Output adder delay for the LVTTL I/O standard	Cload = 35 pF Rup = 564.5 Ω Rdn = 430 Ω *(2)*
2.5 V	Output adder delay for the 2.5-V I/O standard	Cload = 35 pF Rup = 450 Ω Rdn = 450 Ω *(2)*
1.8 V	Output adder delay for the 1.8-V I/O standard	Cload = 35 pF Rup = 520 Ω Rdn = 480 Ω *(2)*
PCI	Output adder delay for the PCI I/O standard	Cload = 10 pF Rup = 1M Ω Rdn = 25 Ω *(2)*
GTl+	Output adder delay for the GTL+ I/O standard	Cload = 30 pF Rup = 25 Ω *(2)*
SSTL-3 Class I	Output adder delay for the SSTL-3 Class I I/O standard	Cload1 = 0 pF Cload2 = 30 pF R = 25 Ω *(2)*
SSTL-3 Class II	Output adder delay for the SSTL-3 Class II I/O standard	Cload1 = 0 pF Cload2 = 30 pF R = 25 Ω *(2)*
SSTL-2 Class I	Output adder delay for the SSTL-2 Class I I/O standard	
SSTL-2 Class II	Output adder delay for the SSTL-2 Class II I/O standard	
LVDS	Output adder delay for the LVDS I/O standard	Cload = 4 pF R=100 Ω *(2)*
CTT	Output adder delay for the CTT I/O standard	
AGP	Output adder delay for the AGP I/O standard	

Note to Tables 42 and 43:

(1) These delays report the differences in delays for different I/O standards. Add the delay for the I/O standard that is used to the external timing parameters.

(2) See Figure 36 for more information.

Table 61. EP20K600C External Bidirectional Timing Parameters

Symbol	-7 Speed Grade		-8 Speed Grade		-9 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{INSUBIDIR}$	2.03		2.57		2.97		ns
$t_{INHBIDIR}$	0.00		0.00		0.00		ns
$t_{OUTCOBIDIR}$	2.00	4.29	2.00	4.77	2.00	5.11	ns
$t_{XZBIDIR}$		8.31		9.14		9.76	ns
$t_{ZXBIDIR}$		8.31		9.14		9.76	ns
$t_{INSUBIDIRPLL}$	3.99		4.77		-		ns
$t_{INHBIDIRPLL}$	0.00		0.00		-		ns
$t_{OUTCOBIDIRPLL}$	0.50	2.37	0.50	2.63	-	-	ns
$t_{XZBIDIRPLL}$		6.35		6.94		-	ns
$t_{ZXBIDIRPLL}$		6.35		6.94		-	ns

Table 62. EP20K1000C f_{MAX} LE Timing Microparameters

Symbol	-7 Speed Grade		-8 Speed Grade		-9 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{SU}	0.01		0.01		0.01		ns
t_{H}	0.10		0.10		0.10		ns
t_{CO}		0.27		0.30		0.32	ns
t_{LUT}		0.66		0.79		0.92	ns

SRAM configuration elements allow APEX 20KC devices to be reconfigured in-circuit by loading new configuration data into the device. Real-time reconfiguration is performed by forcing the device into command mode with a device pin, loading different configuration data, reinitializing the device, and resuming user-mode operation. In-field upgrades can be performed by distributing new configuration files.

Configuration Schemes

The configuration data for an APEX 20KC device can be loaded with one of five configuration schemes (see Table 70), chosen on the basis of the target application. An EPC16, EPC2, or EPC1 configuration device, intelligent controller, or the JTAG port can be used to control the configuration of an APEX 20KC device. When a configuration device is used, the system can configure automatically at system power-up.

Multiple APEX 20KC devices can be configured in any of five configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Table 70. Data Sources for Configuration

Configuration Scheme	Data Source
Configuration device	EPC16, EPC8, EPC4, EPC2, or EPC1 configuration device
Passive serial (PS)	MasterBlaster or ByteBlasterMV download cable or serial data source
Passive parallel asynchronous (PPA)	Parallel data source
Passive parallel synchronous (PPS)	Parallel data source
JTAG	MasterBlaster or ByteBlasterMV download cable or a microprocessor with a Jam Standard Test and Programming Language (STAPL) or JBC File

For more information on configuration, see *Application Note 116 (Configuring SRAM-Based LUT Devices)*.

Device Pin-Outs

See the Altera web site **(http://www.altera.com)** or the ***Altera Digital Library*** for pin-out information.

Ordering Information

Figure 39 describes the ordering codes for Stratix devices. For more information on a specific package, refer to the *Altera Device Package Information Data Sheet*.

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